

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| In re Application of Bateman et al. |) | |
| |) Art Unit: | N/A |
| |) | |
| Serial Number: |) Examiner: | N/A |
| |) | |
| Filed: |) Atty Docket: | DEH073 |
| Herewith | | |

For: Mass Spectrometer

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to Rule 37 C.F.R. §1.51(b), §1.56, §1.97, and §1.98, this Information Disclosure Statement is submitted in the above-identified patent application. A listing of documents to be published on the face of any patent granted from this application is submitted herewith on Form PTO-1449 with a copy thereof.

CONCISE STATEMENT OF RELEVANCY
(Non-English Language Documents Only)

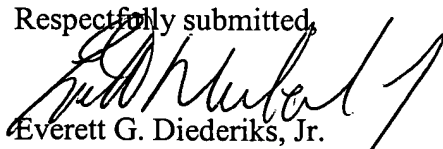
The foreign language references cited in the Information Disclosure Statement generally pertain to ion guides and mass spectrometers. Abstracts in English are being provided to aid the Examiner in considering the potential relevancy of the cited documents.

CERTIFICATION

This Information Disclosure Statement is submitted within three months of the filing date of and/or prior to the issuance of a first Office Action in the above-identified U.S. patent application.

The Examiner is requested to acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

Respectfully submitted,


Everett G. Diederiks, Jr.
Attorney for Applicant
Registration No. 33,323

Date: April 22, 2004

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| FORM PTO 1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT | ATTY DOCKET NO. DEH073 | SERIAL NO. N/A |
| | APPLICANT Bateman et al. | |
| | FILING DATE Herewith | GROUP N/A |

U.S. Patent Documents

| Examiner Initial | Document Number | Date | Patentee/Applicant | Class | Subclass | Filing Date if Appropriate |
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| Examiner | Date Considered |
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Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.